

C2
an underlayer which comprises a first underlayer containing chromium as a principal component thereof, a second and sputtered underlayer consisting of nickel and phosphorus and a third underlayer containing chromium as a principal component thereof which are formed in the described order, [in the presence or absence of a first underlayer containing chromium as a principal component thereof, on said substrate, and]

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said second underlayer has a thickness of not less than 5nm, contains P in the concentration of 15 to 33 atom % in the NiP layer and has a textured structure formed upon mechanical treatment, and

a magnetic recording layer which has a circumferential direction of easy magnetization and contains cobalt as a principal component thereof, and also contains chromium and platinum in combination with tantalum or tantalum and niobium.

✓
Please cancel claim 4 without prejudice.

✓
Please cancel claims 10 and 11 without prejudice.

REMARKS

The specification and claims have been amended to overcome the outstanding objections. In addition, the claims have been amended to overcome the outstanding §112, paragraph 6 rejections, without narrowing the scope of the claims. Among other things, the features of canceled claim 4 are now included in amended claim 1.

Claims 1, 2, 5-8 and 8-12 stand rejected under §103 on the basis of Tani et al. in view of Okuyama et al. Since features of claim 4 are now included in claim 1, this rejection is moot.